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		Application Number	10/571183	
		Filing Date	03/09/2006	
		First named Inventor	James Edmond Bateman	
		Group Art Unit	2881	
	(use as many sheets as necessary)	Examiner name	Vanore	
	Sheet 1 of 2	Attorney Docket Number	063511-9088-00	
		U.S. Patent Documents		
Examiner Initials	U.S. Patent Document Number	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited	
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		N DATENT DOCUMENTS		

FOREIGN PATENT DOCUMENTS							
Examiner Initials		Country Code	Foreign Patent Document Number	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document	Translation	English Abstract
/D.V./		wo	9306470	European Economic Community	04/01/1993		

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS				
Examiner Initials		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, pages(s), volume-issue numbers(s), publisher, city and/or country where published.		
	/D.V./	R. A. ROSENBERG, J. K. SIMONS, and S. P. FRIGO, "X-ray fluorescence detection of low-Z elements using a microchannel plate detector," <i>Review of Scientific Instruments</i> , vol. 63, no. 4, Part 1, April 1992 (1992-04), p. 2193-2194, XP002305295, 1992, American Institute of Physics.		

Examiner // Signature	David Vanore/	Date Considered	06/11/2008
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Sheet 2 of 2	Attorney Docket Number	063511-9088-00	

	OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS				
/D.V./	MASOUD KASRAI ET AL, "X-ray fluorescence measurements of X-ray absorption near edge structure at the Si, P, and S L edges," <i>Journal of Vacuum Science & Technology A (Vacuum, Surfaces, and Films)</i> , vol. 11, no. 5, September-October 1993, p. 2694-2699, XP002305296, ISSN: 0734-2101, p. 2694, right-hand column, p. 2695, right-hand column, paragraph 2, American Vacuum Society, USA.				
/D.V./	J. E. BATEMAN ET AL, "Studies of the Gain Properties of Microstrip Gas Counters Relevant to Their Application as X-Ray and Electron Detectors," <i>IEEE Transactions on Nuclear Science</i> , vol. 49, no. 4, August 2002 (2002-08), p. 1644-1650, XP002305297, p. 1649, 2002, IEEE Nuclear and Plasma Sciences Society.				
/D.V./	G. TOURILLON ET AL, "Electron yield X-ray absorption spectroscopy at atmospheric pressure," <i>Physics Letters A</i> , vol. 121, no. 5, 27 April 1987, p. 251-257, XP009039581, ISSN: 0375-9601, p. 251 and p. 255, Elsevier Science Publishers B.V., The Netherlands.				
/D.V./	M. E. KORDESCH and R. W. HOFFMAN, "Electron-yield extended X-ray absorption fine structure with the use of a gas-flow electron detector," <i>Physical Review B (Condensed Matter) USA</i> , vol. 29, no. 1, January-June 1984, p. 491-492, XP002305299, ISSN: 0163-1829, entire document, The American Physical Society.				

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Signature		Considered	

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